Searcn	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/798,469	LEE ET AL.	
Examiner	Art Unit	
VanThu Nouven	2824	

SEARCHED				
Class	Subclass	Date	Examiner	
365	189.01 189.04 x 190 x 230.01	11/10/2005	VTN	
	230.03 x			
Updated	search	3/2/06	VIW	
			i .	
				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST search (see print out history)	11/4/2005	VTN	
EAST search (see print out history)	3/18/06	VTIV	
•		,	